

Search Notes

Application/Control No.

09/912,721

Examiner

JOHN J. LEE

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	560,445 453,434 561,424 514,507	12/20/2008	J.L
455	510,515	12/20/2008	J.L
712	30,34	12/20/2008	J.L

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	12/20/2008	J.L